



ALPHA & OMEGA
SEMICONDUCTOR

AOD468/AOI468

300V, 11.5A N-Channel MOSFET

General Description

The AOD468 & AOI468 have been fabricated using an advanced high voltage MOSFET process that is designed to deliver high levels of performance and robustness in popular AC-DC applications. By providing low $R_{DS(on)}$, C_{iss} and C_{rss} along with guaranteed avalanche capability these parts can be adopted quickly into new and existing offline power supply designs. These parts are ideal for boost converters and synchronous rectifiers for consumer, telecom, industrial power supplies and LED backlighting.

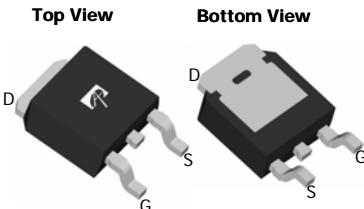
Product Summary

V_{DS}	350V@150°C
I_D (at $V_{GS}=10V$)	11.5A
$R_{DS(ON)}$ (at $V_{GS}=10V$)	<0.42Ω

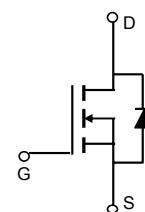
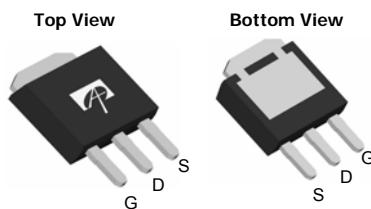
100% UIS Tested!
100% R_g Tested!



TO252
DPAK



TO251A
IPAK



Absolute Maximum Ratings $T_A=25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	V_{DS}	300	V
Gate-Source Voltage	V_{GS}	± 30	V
Continuous Drain Current ^B	I_D	11.5	A
$T_C=100^\circ\text{C}$		8.3	
Pulsed Drain Current ^C	I_{DM}	29	
Avalanche Current ^C	I_{AR}	3.8	A
Repetitive avalanche energy ^C	E_{AR}	216	mJ
Single pulsed avalanche energy ^H	E_{AS}	430	mJ
Peak diode recovery dv/dt	dv/dt	5	V/ns
$T_C=25^\circ\text{C}$	P_D	150	W
Power Dissipation ^B		1	W/°C
Junction and Storage Temperature Range	T_J , T_{STG}	-50 to 175	°C
Maximum lead temperature for soldering purpose, 1/8" from case for 5 seconds	T_L	300	°C

Thermal Characteristics

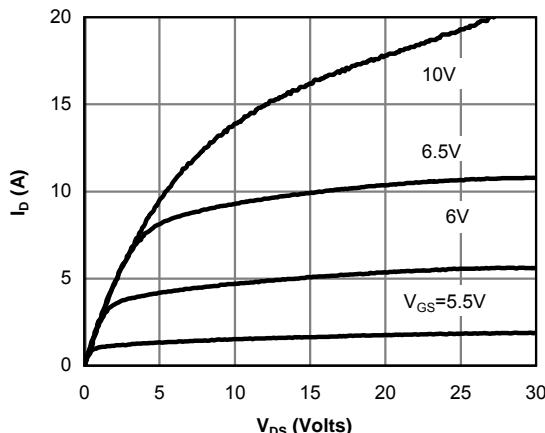
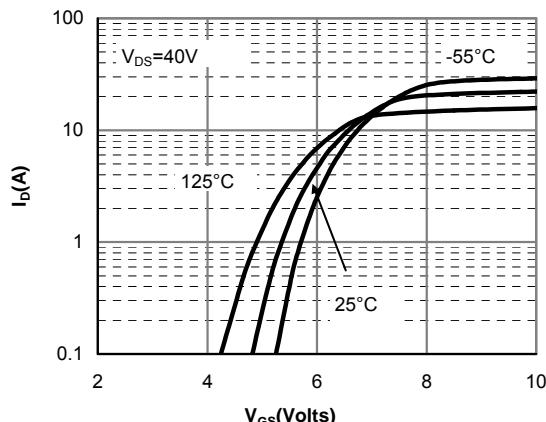
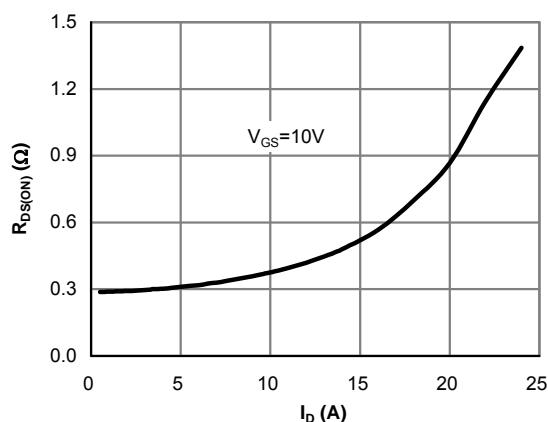
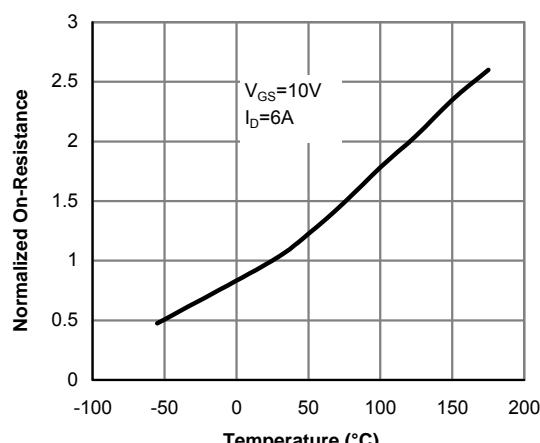
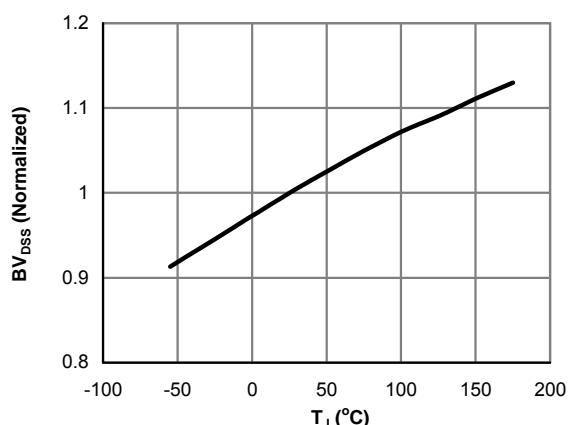
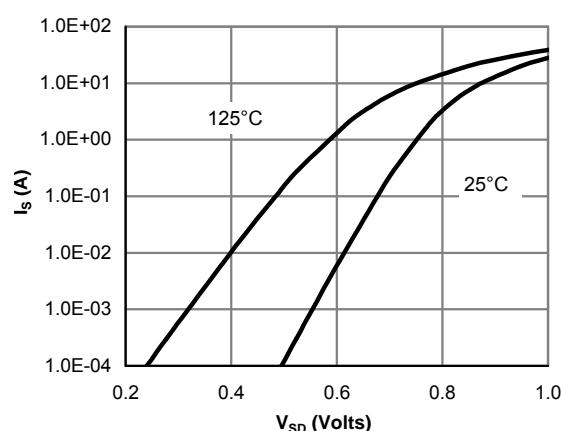
Parameter	Symbol	Typical	Maximum	Units
Maximum Junction-to-Ambient ^{A,G}	$R_{\theta JA}$	45	55	°C/W
Maximum Case-to-sink ^A	$R_{\theta CS}$	-	0.5	°C/W
Maximum Junction-to-Case ^{D,F}	$R_{\theta JC}$	0.7	1	°C/W

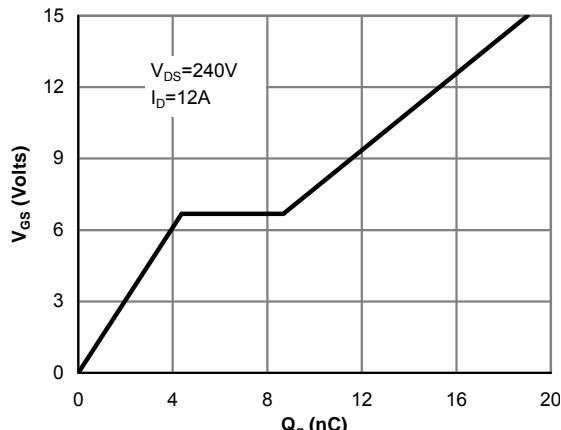
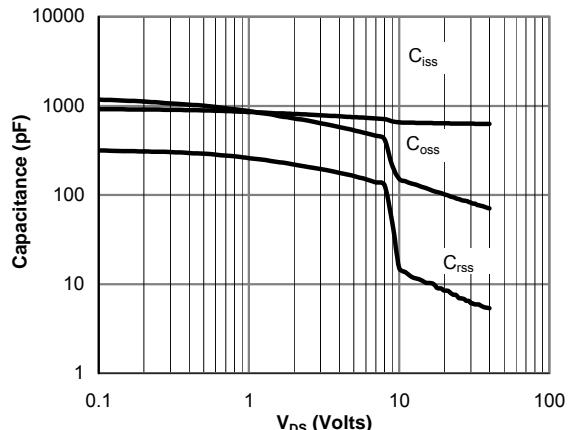
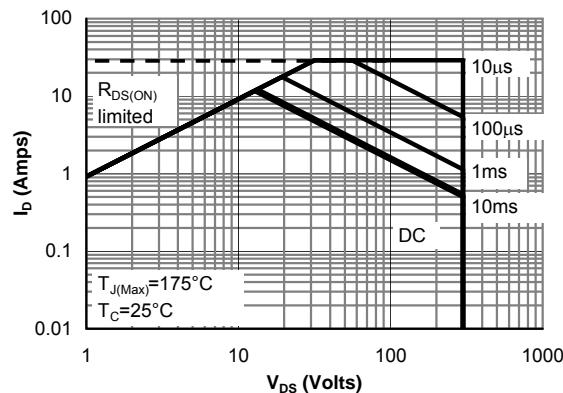
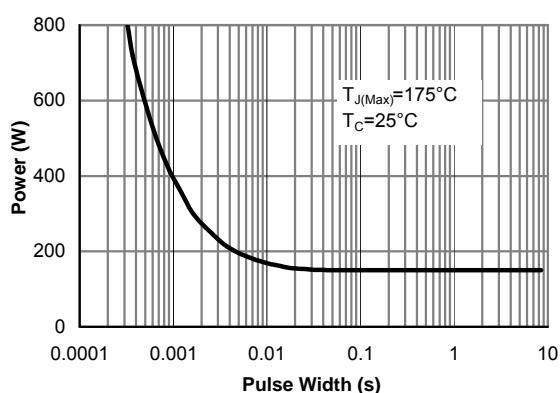
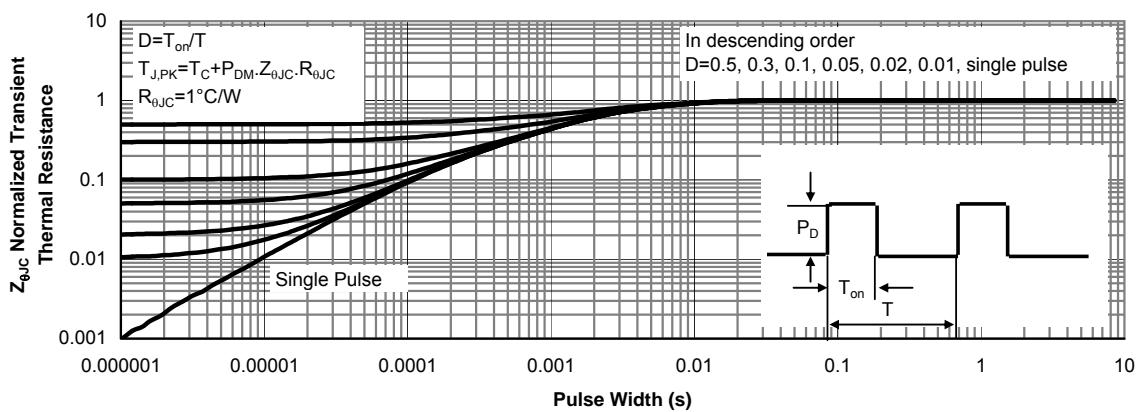
Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}, V_{GS}=0\text{V}, T_J=25^\circ\text{C}$	300			V
		$I_D=250\mu\text{A}, V_{GS}=0\text{V}, T_J=150^\circ\text{C}$		350		
$BV_{DSS}/\Delta T_J$	Zero Gate Voltage Drain Current	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$		0.29		$\text{V}/^\circ\text{C}$
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=300\text{V}, V_{GS}=0\text{V}$		1		μA
		$V_{DS}=240\text{V}, T_J=125^\circ\text{C}$		10		
I_{GSS}	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm 30\text{V}$			± 100	nA
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=5\text{V}, I_D=250\mu\text{A}$	3.4	4	4.5	V
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance	$V_{GS}=10\text{V}, I_D=6\text{A}$		0.31	0.42	Ω
g_{FS}	Forward Transconductance	$V_{DS}=40\text{V}, I_D=6\text{A}$		11		S
V_{SD}	Diode Forward Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$		0.74	1	V
I_S	Maximum Body-Diode Continuous Current				12	A
I_{SM}	Maximum Body-Diode Pulsed Current				29	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=25\text{V}, f=1\text{MHz}$	500	632	790	pF
C_{oss}	Output Capacitance		55	90	125	pF
C_{rss}	Reverse Transfer Capacitance		3	7	11	pF
R_g	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$	1.3	2.7	4.1	Ω
SWITCHING PARAMETERS						
Q_g	Total Gate Charge	$V_{GS}=10\text{V}, V_{DS}=240\text{V}, I_D=12\text{A}$	10	12.8	16	nC
Q_{gs}	Gate Source Charge			4.4		nC
Q_{gd}	Gate Drain Charge			4.3		nC
$t_{D(\text{on})}$	Turn-On Delay Time	$V_{GS}=10\text{V}, V_{DS}=150\text{V}, I_D=12\text{A}, R_G=25\Omega$		18		ns
t_r	Turn-On Rise Time			31		ns
$t_{D(\text{off})}$	Turn-Off Delay Time			36		ns
t_f	Turn-Off Fall Time			20		ns
t_{rr}	Body Diode Reverse Recovery Time	$I_F=12\text{A}, dI/dt=100\text{A}/\mu\text{s}, V_{DS}=100\text{V}$	130	170	205	ns
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F=12\text{A}, dI/dt=100\text{A}/\mu\text{s}, V_{DS}=100\text{V}$	1	1.3	1.6	μC

- A. The value of $R_{\text{on},A}$ is measured with the device in a still air environment with $T_A=25^\circ\text{C}$.
- B. The power dissipation P_D is based on $T_{J(\text{MAX})}=175^\circ\text{C}$ in a TO252 package, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.
- C. Repetitive rating, pulse width limited by junction temperature $T_{J(\text{MAX})}=175^\circ\text{C}$.
- D. The $R_{\text{on},A}$ is the sum of the thermal impedance from junction to case R_{JJC} and case to ambient.
- E. The static characteristics in Figures 1 to 6 are obtained using $<300\ \mu\text{s}$ pulses, duty cycle 0.5% max.
- F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of $T_{J(\text{MAX})}=175^\circ\text{C}$.
- G. These tests are performed with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$.
- H. $L=60\text{mH}, I_{AS}=3.8\text{A}, V_{DD}=150\text{V}, R_G=10\Omega$, Starting $T_J=25^\circ\text{C}$

THIS PRODUCT HAS BEEN DESIGNED AND QUALIFIED FOR THE CONSUMER MARKET. APPLICATIONS OR USES AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS ARE NOT AUTHORIZED. AOS DOES NOT ASSUME ANY LIABILITY ARISING OUT OF SUCH APPLICATIONS OR USES OF ITS PRODUCTS. AOS RESERVES THE RIGHT TO IMPROVE PRODUCT DESIGN, FUNCTIONS AND RELIABILITY WITHOUT NOTICE.

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Fig 1: On-Region Characteristics

Figure 2: Transfer Characteristics

Figure 3: On-Resistance vs. Drain Current and Gate Voltage

Figure 4: On-Resistance vs. Junction Temperature

Figure 5: Break Down vs. Junction Temperature

Figure 6: Body-Diode Characteristics

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Figure 7: Gate-Charge Characteristics

Figure 8: Capacitance Characteristics

Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

Figure 10: Single Pulse Power Rating Junction-to-Case (Note F)

Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

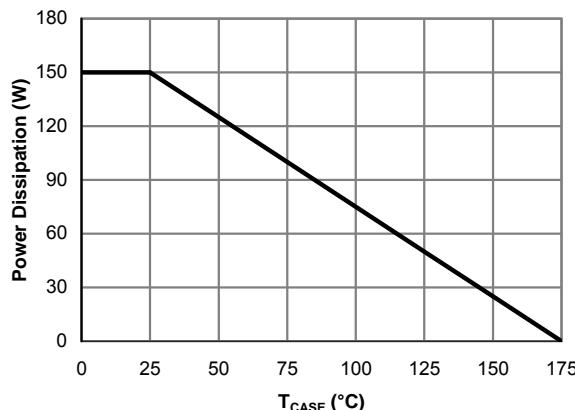
TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS


Figure 12: Power De-rating (Note B)

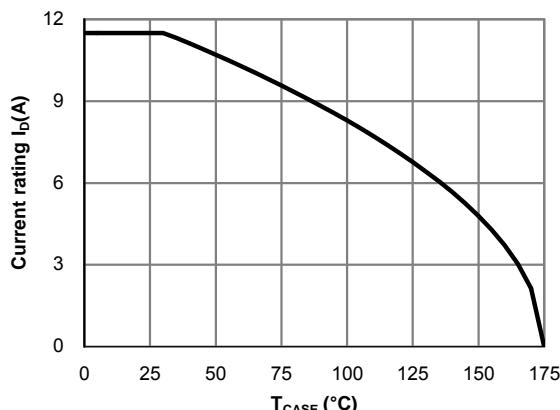


Figure 13: Current De-rating (Note B)

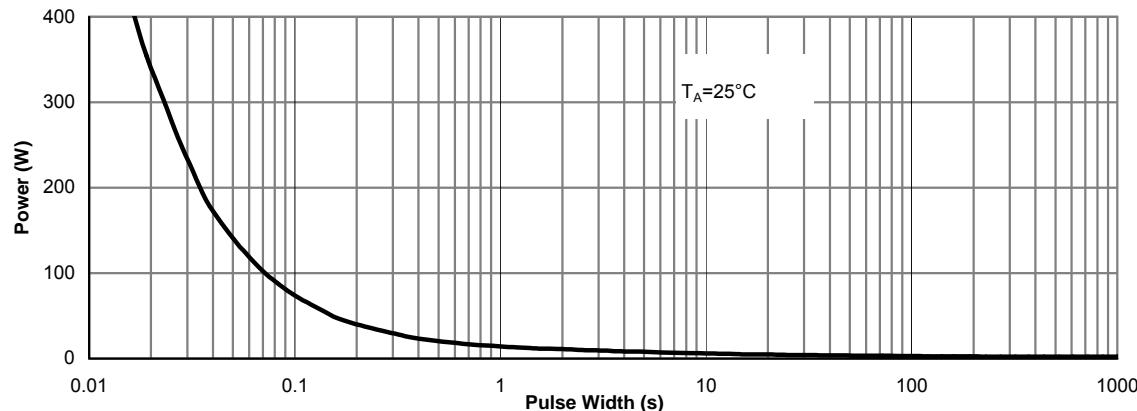


Figure 14: Single Pulse Power Rating Junction-to-Ambient (Note G)

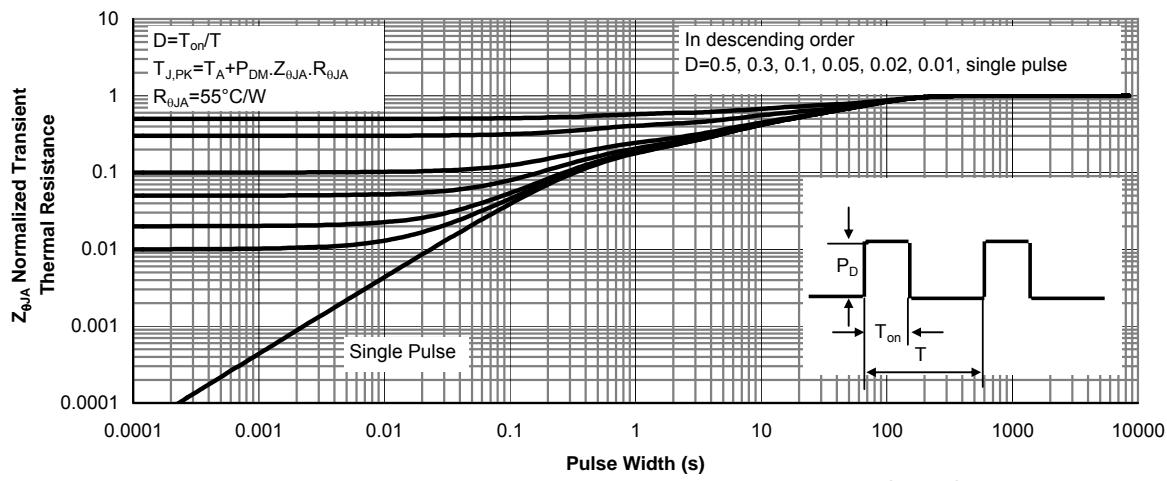
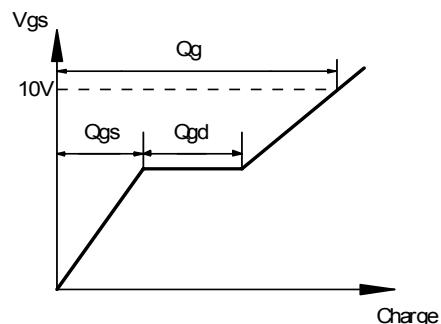
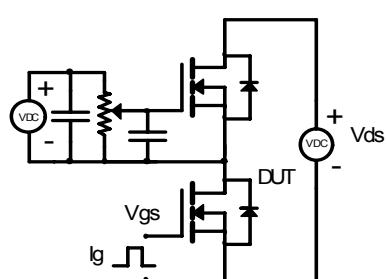
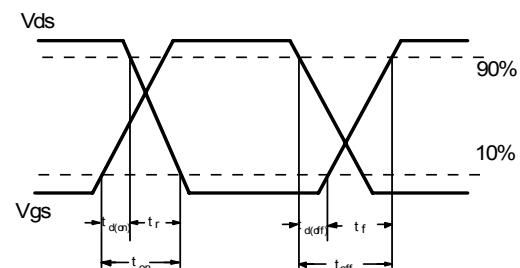
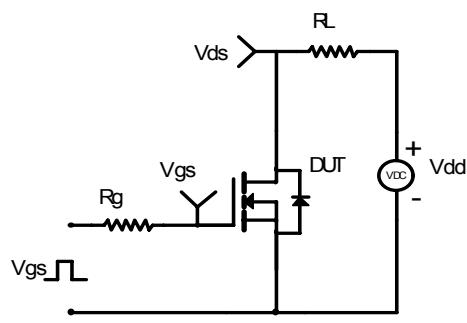
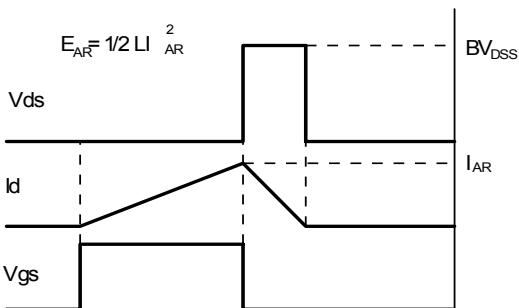
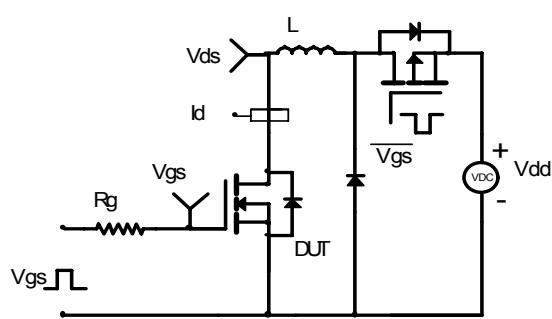


Figure 15: Normalized Maximum Transient Thermal Impedance (Note G)

Gate Charge Test Circuit & Waveform

Resistive Switching Test Circuit & Waveforms

Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

Diode Recovery Test Circuit & Waveforms
